

Page 1 of 1 FORM PTO-1449 MAY 28 2004 LIST OF PATENTS AND PUBLICATIONS FOR APPLICANT'S INFORMATION DISCLOSURE STATEMENT	Atty. Docket No.: H0004978(1100.1206101)	Serial No.: 10/671,930
	Applicant: Ulrich Bonne	
	Filing Date: September 26, 2003	Group Art: unknown

U.S. PATENT DOCUMENTS

Examiner Initial	Document No.	Date	Name	
KAM	4,324,566	04/1982	Jacob et al.	
KAM	5,196,039	03/19913	Phillips et al.	
KAM	5,442,175	08/1995	Dawson	
KAM	6,131,440	10/2000	Bertrand	
KAM	6,413,781	07/2002	Geis et al.	

FOREIGN PATENT DOCUMENTS

Examiner Initial	Document No.	Date	Country	Translation Yes No

OTHER ART (Including Author, Title, Date, Pertinent Pages, etc.)

EXAMINER: <i>Beri D...</i>	DATE CONSIDERED: <i>1/13/06</i>

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U.S. PATENT DOCUMENTS

Examiner Initial	Document No.	Date	Name	
KAM	5,135,549	08/04/1992	Phillips et al.	<u> </u>
KAM	6,169,965	01/02/2001	Kubisiak et al.	<u> </u>


FOREIGN PATENT DOCUMENTS

Examiner Initial	Document No.	Date	Country	Translation Yes No
KAM	WO 00/61261	10/19/2000	PCT	<u> </u>

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U.S. PATENT DOCUMENTS

Examiner Initial	Document No.	Date	Name	Class	Sub Class	Filing Date If Appropriate
KAM	3,146,616	09/1964	Loyd			
KAM	3,557,532	01/1971	Broerman			
KAM	3,783,356	01/1974	Lide, III et al.			
KAM	4,043,196	08/1977	Trageser			
KAM	4,228,815	10/1980	Juffa et al.			
KAM	4,478,076	10/1984	Bohrer			
KAM	4,483,200	11/1984	Togawa et al.			
KAM	4,507,974	04/1985	Yelderman			
KAM	4,576,050	03/1986	Lambert			
KAM	4,735,082	04/1988	Kolloff			
KAM	4,759,210	07/1988	Wohltjen			
KAM	4,909,078	03/1990	Sittler et al.			
KAM	4,944,035	07/1990	Aagardl Roger L., et al.			
KAM	5,031,126	07/1991	McCulloch et al.			
KAM	5,044,766	09/1991	Stuart			
KAM	5,056,047	10/1991	Sondergeld			
KAM	5,146,414	09/1992	McKown et al.			
KAM	5,243,858	09/1993	Erskine et al.			
KAM	5,263,380	11/1993	Sultan et al.			
KAM	5,268,302	12/1993	Rounbehler et al.			
KAM	5,379,630	01/1995	Lacey			
KAM	5,463,899	11/1995	Zemel et al.			
KAM	5,533,412	07/1996	Jerman et al.			
KAM	5,587,520	12/1996	Rhodes			
KAM	5,922,974	07/1999	Davidson et al.			

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KAM	6,016,027	01/2000	DeTemple et al.			
KAM	6,139,384	10/2000	DeTemple et al.			
KAM	6,178,811	01/2001	Bonne et al.			
KAM	6,194,833	02/2001	DeTemple et al.			
KAM	6,308,553	10/2001	Bonne et al.			
KAM	6,393,894	05/2002	Bonne et al.			
KAM	6,494,617	12/2002	Stokes et al.			

FOREIGN PATENT DOCUMENTS

Examiner Initial	Document No.	Date	Country	Translation Yes No
KAM	DE 196 19 133 A1	11/13/97	Germany	Abstract
KAM	DE 2 934 566 A1	03/19/81	Germany	
KAM	DE 32 34 146 A1	03/15/84	Germany	
KAM	DE 42 22 458 A1	01/13/94	Germany	Abstract
KAM	DE 42 43 573 A1	06/23/94	Germany	
KAM	DE 296 07 315 U1	09/26/96	Germany	
KAM	EP 0 232 719 A1	01/10/87	Europe	Abstract
KAM	EP 0 348 245 A2	12/27/89	Europe	
KAM	EP 0 364 982 A2	04/25/90	Europe	
KAM	EP 0 419 873 A2	08/29/90	Europe	
KAM	EP 0 468 793 A2	01/29/92	Europe	
KAM	EP 0 702 212 A2	03/20/96	Europe	
KAM	EP 0 773 432 A2	05/14/97	Europe	Abstract
KAM	GB 2 287 792 A	09/1995	United Kingdom	
KAM	56-153256	11/1981	Japan	Abstract

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KAM	57-131029	08/1982	Japan	Abstract
KAM	57-206830	12/1982	Japan	Abstract
KAM	WO 92/06369	04/1992	PCT	
KAM	WO 94/20825	09/1994	PCT	
KAM	WO 98/22793	05/1998	PCT	

OTHER ART (Including Author, Title, Date, Pertinent Pages, Etc.)

KAM	—	Atalla et al., "Radiation Effects with the AC Heated Strip Technique for the Measurement of Thermal Properties of Liquids", <u>High Temperatures - High Pressures</u> , Vol. 17, pages 447-452, 1985.
KAM	—	Atalla et al. "Measurement of Thermal Properties of Liquids with an AC Heated-Wire Technique", <u>International Journal of Thermophysics</u> , Vol. 2, No. 2, 1981.
T208 KAM	—	Bonne et al., "Industrial Wireless PHASED Sensor Phase 1. Feasibility Demonstration," Progress Report for 4th Quarter of 2002, pp. 1-17, January 31, 2002.
T208 KAM	—	Bonne, et al., "PHASED: a Faster, Smarter and More Affordable Gas Analysis Device," 16th International Forum on Process Analytical Chemistry, San Diego, CA., January 22-25, 2002, pp 1-17.
KAM	—	Bonne, U., et al., "New Gas Composition and Trace Contaminant Sensors," GTI Natural Gas Technologies Conference, Orland, FL, Sept. 30 - Oct. 2, 2002, pages 1-12.
KAM	—	Cabuz, C. et al., "Mesoscopic Sampler Based on 3-DF Arrays of Electrostatically Actuated Diaphragms," Proc. 10th Conf. S.S. S&A. Transducers '99 7-12 June '99, Sendai, Japan.
KAM	—	Cabuz, C., et al., "The Dual Diaphragm Pump," IEEE, pages 519-522, 2001.
KAM	—	Dipl.-Ing. Dr. techn. Wolfgang Wehrmann et al., "Korrelationstechnik", <u>Expert Verlag</u> , Grafenau, XP002094984, 173 pages, 1980.
KAM	—	Fuggerth, Endre, "Zone Gas Chromatography," <u>Analytical Chemistry</u> , 61, no. 14, pp. 1478-1485, (1989).
KAM	—	Honeywell Electronic Materials Interconnect Solutions, Thin Films - Dielectrics, Comparison of Solution and Film Properties, Advanced Products for IC Fabrication, 1 page.
T208 KAM	—	http://www.advanced-polymers.com/star_center/techincal_papers/reduction_in_effective_dielectric_constant.pdf , 1 page.
T208 KAM	—	http://www.chrompack.com/cgi/applicsvie?ap=A00607&Go=G0 , NexTrieve document view, 2 pages, printed December 26, 2002.
T208 KAM	—	http://www.zoex.com/html/technote_kt030505-1.html , Zoex Corporation, "A New Window on the Che," 5 pages, printed March 15, 2004.
KAM	—	International Search Report, PCT/US00/19924, mailed March 5, 2001, 7 pages.

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KAM	—	Kenndler, Ernst, "Gas Chromatography," Institute for Analytical Chemistry, University of Vienna, pages 1-34, September 9, 1999
KAM	—	Kindlund et al., "Quartz Crystal Gas Monitor With Gas Concentrating Stage," Sensors and Actuators, 6 (1984) pp.1-17.
KAM	—	NexTrieve document view, http://www.chrompack.com/cgi/applicsvie?ap=A00764 , 2 pages.
1208 KAM	—	Park, et al., "Microdischarge Arrays: A New Family of Photonic Devices (Revised)," IEEE Journal on Selected Topics in Quantum Electronics, Vol. 8, No. 2, pp. 387-394, March/April 2002.
1208 KAM	—	Park, et al., "Photodetection in the visible, ultraviolet, and near-infrared with silicon microdischarge devices," Applied Physics Letters, Vol. 81, No. 24, pp. 4529-4531, December 9, 2002.
1208 KAM	—	Park, et al., : Arrays of silicon micro discharge devices with multicomponent dielectrics," Optics Letters, Vol. 26, No. 22, pp. 1773-1775, November 15, 2001.
KAM	—	Phillips, J.B. et al., "Thermal Modulation: A Chemical Instrumentation Component of Potential Value in Improving Portability," Field Analytical Chemistry and Technology, 1(1): 23-29, 1996.
1208 KAM	—	Quimby, et al., " Evaluation of a Microwave Cavity, Discharge Tube, and Gas Flow System of Combined Aas Chromatography - Atomic Emission Detection," Analytical Chemistry, Vol. 62, No. 10, pp. 1027-1034, May 15, 1990.
KAM	—	Stevenson, Robert, "Wintergreen '97," The World of Separation Science, The 19th International Symposium on Capillary Chromatography and Electrophoresis, 11 pages.
KAM	—	Toker et al., "Design and development of a fiber optic TDI CCD-based slot-scan digital mammography system," X-ray Detector Physics and Applications II, Proceedings SPIE-The International Society for Optical Engineering, vol. 2009 (July 13-14, 1993) pp.246-252.
KAM	—	Whitman et al., "Double-Injection FIA Using First-Order Calibration for Multicomponent Analysis," Analytical Chemistry 63 (1991) pp.775-781.

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